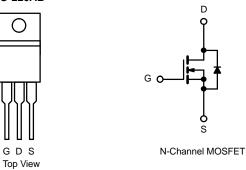


05N03LB-VB TO220 Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	30			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0. 003			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0. 004			
I _D (A)	120			
Configuration	Single			

TO-220AB



FEATURES

- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested
 Compliant to RoHS Directive 2011/65/EU

APPLICATIONS

- OR-ing
- Server
- DC/DC

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	30	V
Gate-Source Voltage		V _{GS}	± 20	
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		120	A
	T _C = 70 °C		60 ^e	
	T _A = 25 °C	I _D	28.8 ^{b, c}	
	T _A = 70 °C		19 ^{b, c}	A
Pulsed Drain Current		I _{DM}	380	1
Avalanche Current Pulse		I _{AS}	36	
Single Pulse Avalanche Energy	Pulse Avalanche Energy L = 0.1 mH		64.8	V
Continuous Source-Drain Diode Current	T _C = 25 °C	L.	90 ^{a, e}	A
	T _A = 25 °C	I _S	3.13 ^{b, c}	A
Maximum Power Dissipation	T _C = 25 °C		250 ^a	
	T _C = 70 °C	P _D	175	10/
	T _A = 25 °C	۲D	3.75 ^{b, c}	- W
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Тур.	Max.	Unit
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	0,00

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 sec.

d. Maximum under steady state conditions is 90 °C/W.
 e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				•			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 µA	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L _ 250 uA		35			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V$, $V_{GS} = \pm 20 V$			± 100	nA	
	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			А	
		V _{GS} = 10 V, I _D = 28.8 A	(<u>^</u>	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 27 A		0.004		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 28.8 A		160		S	
Dynamic ^b				-	1		
Input Capacitance	C _{iss}			3100			
Output Capacitance	C _{oss}		725		pF		
Reverse Transfer Capacitance	C _{rss}			370		-	
		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 28.8 A		171	257		
Total Gate Charge	Qg	V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 28.8 A		81.5	123	nC	
Gate-Source Charge	Q _{gs}			34			
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	V_{DD} = 15 V, R_{L} = 0.625 Ω		11	17	-	
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 15 \text{ V}, \text{ R}_{L} = 0.625 \Omega$ $I_{D} \cong 24 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{g} = 1 \Omega$		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V _{DD} = 15 V, R _L = 0.67 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		55	83	1	
Fall Time	t _f			12	18	1	
Drain-Source Body Diode Characteristic	s				1	L	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			90		
Pulse Diode Forward Current ^a	I _{SM}				90	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		27		1	
Reverse Recovery Rise Time	t _b			25		ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

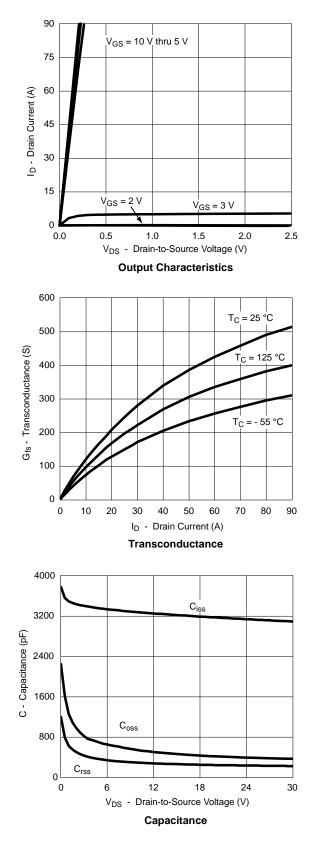
b. Guaranteed by design, not subject to production testing.

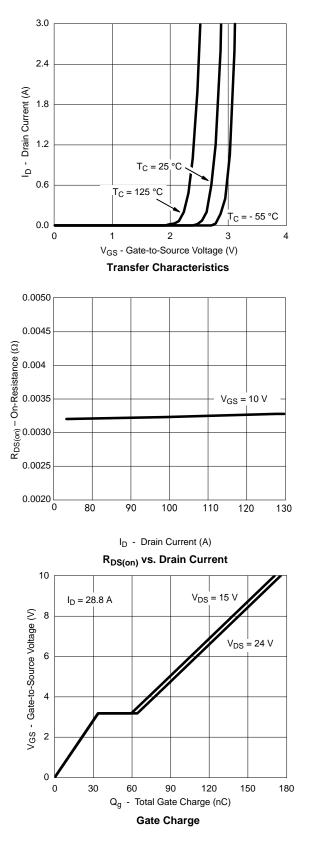
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

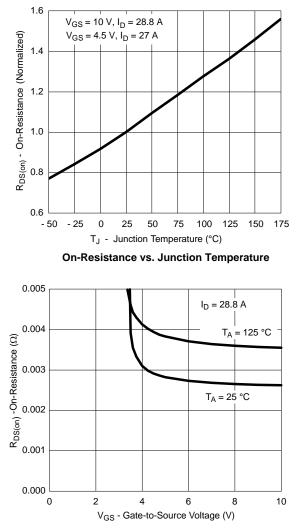




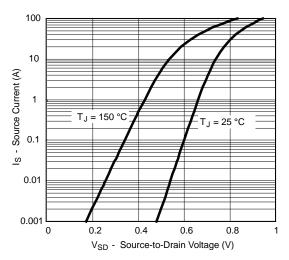
服务热线:400-655-8788



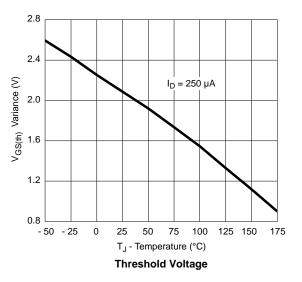
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

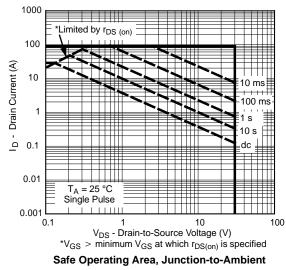


 $R_{DS(on)}$ vs. V_{GS} vs. Temperature









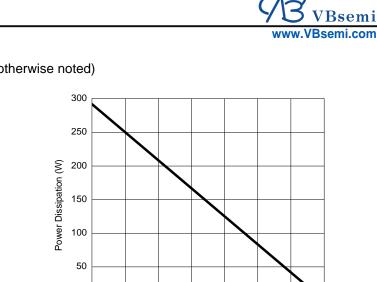
Package Limited

T_C - Case Temperature (°C)

Current Derating*

0 L

I_D - Drain Current (A)

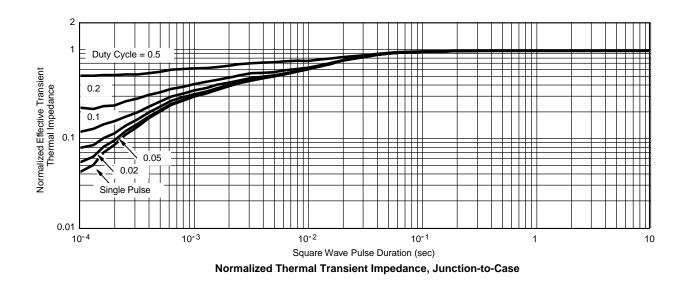


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

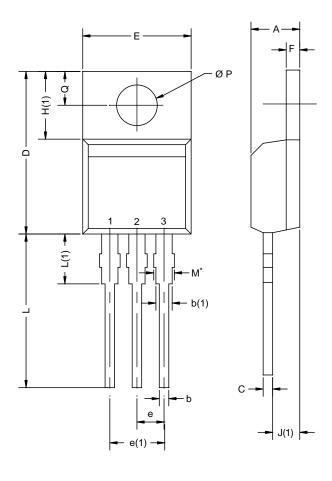
T_C - Case Temperature (°C)

Power Derating





TO-220AB



MIN. 4.25 0.69 1.20	MAX. 4.65 1.01	MIN. 0.167	MAX.
0.69		0.167	0 1 9 2
	1.01		0.103
1.20		0.027	0.040
	1.73	0.047	0.068
0.36	0.61	0.014	0.024
14.85	15.49	0.585	0.610
10.04	10.51	0.395	0.414
2.41	2.67	0.095	0.105
4.88	5.28	0.192	0.208
1.14	1.40	0.045	0.055
6.09	6.48	0.240	0.255
2.41	2.92	0.095	0.115
13.35	14.02	0.526	0.552
3.32	3.82	0.131	0.150
3.54	3.94	0.139	0.155
2.60	3.00	0.102	0.118
	10.04 2.41 4.88 1.14 6.09 2.41 13.35 3.32 3.54 2.60	10.04 10.51 2.41 2.67 4.88 5.28 1.14 1.40 6.09 6.48 2.41 2.92 13.35 14.02 3.32 3.82 3.54 3.94	10.0410.510.3952.412.670.0954.885.280.1921.141.400.0456.096.480.2402.412.920.09513.3514.020.5263.323.820.1313.543.940.1392.603.000.102

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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